Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/083,886	CHENG ET AL.
Examiner	Art Unit
Huyen X. Vo	2655

SEARCHED					
Class	Subclass	Date	Examiner		
704	200.1; 219-223	1/19/2006	HV		
704	500-503	1/19/2006	HV		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Inter	jerene	Search)	neluded		
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
Update EAST search included IEEE search	1/19/2006	HV
		
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